Product Specification 108-115008

Shield Finger Scalable Height From 1.24mm to 3.4mm

1. SCOPE

1.1. Content

This specification covers the requirements for product performance test methods and quality assurance provisions of the scalable spring finger. Applicable product descriptions and part numbers are as shown in Appendix 1.

1.2. Qualification

When tests are performed on the subject product line, procedures specified in Figure 2 shall be used. All inspections shall be performed using the applicable inspection plan and product drawing.

2. APPLICABLE DOCUMENTS

The following documents form a part of this specification to the extent specified herein. Unless otherwise specified, the latest edition of the document applies. In the event of conflict between the requirements of this specification and the product drawing, the product drawing shall take precedence. In the event of conflict between the requirements of this specification and the referenced documents, this specification shall take precedence.

2.1. Tyco Electronics Documents

501-115009-*: Qualification Test Report

2.2. Commercial Standard and Specifications:

Test Methods for Electronic Component Parts: MIL-STD-202.

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3. REQUIREMENTS:

3.1. Design and Construction:

Product shall be of the design, construction and physical dimensions specified on the applicable product drawing.

3.2. Materials:

Material used in the construction of this product shall be as specified on the applicable product drawing.

3.3. Ratings

A. Voltage: 12 volts AC

B. Current: 0.5A

C. Temperature: -40 °C to 85 °C

3.4. Performance and Test Description

Product is designed to meet the electrical, mechanical and environmental performance requirements specified in Figure 1. Unless otherwise specified, all tests shall be performed at ambient environmental conditions.

3.5. Test Requirements and Procedures Summary

Para.	Test Items	Requirements	Procedures
3.5.1	Initial examination of Product	Meets requirements of product drawing	Visual inspection. EIA-364-18.
3.5.2	Final examination of Product	Meets visual requirements	Visual inspection. EIA-364-18.
		Electrical Requirement	S
3.5.3	Low Level Contact Resistance(LLCR)	Initial: 80 m Ω Max. Final: Δ R 25 m Ω Max.	Subject mated specimens to 20 mV Max open circuit at 100 mA DC. In acc. with IEC 60512-2 test 2a
3.5.4	Temperature Rise	30 ℃ Max. under loaded rating current	The voltage / Current should be applied to the contacts for 1 hours as below. Voltage: 5V D.C Current: 0.7A
	1	Mechanical Requirement	nts
3.5.5	Normal Force	Normal Force at nominal height: 0.60+/-0.2N.	Stroke the spring top to the nominal working height
3.5.6	Durability	Normal Force at nominal height: 0.60+/-0.2N. 80 milliohms Max.(Initial) ΔR 25 milliohms Maximum.(Final)	No. of cycles: 10 cycles. Stroke the spring top to the nominal working height

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3.5.7	Shock	No discontinuities of 1 microsecond or longer duration.			Subject mated specimens to 30G's half-sine shock pulses of 6 milliseconds duration. Three shocks			
		80 milliohms M ΔR 25 milliohm	S	ıl)	mutually	lirection applied ald perpendicular plan	-	
		Maximum.(Fina	al)		shocks. See Figu	re 3		
3.5.8	Vibration, Random	No discontinuiti			Subject r working h 5 Hz	•	at nomin	а
		duration. 80 milliohms M		ıl)	12 Hz	0.1m2/s3 2.2 m2/s3		
		ΔR 25 milliohm Maximum.(Fina	_		20Hz 200Hz	2.2. m2/s3 0.04 m2/s3		
					•	0.04 m2/s3 ture: 23+/-5℃.		
					2 hours f	: 35~70%RH. or X&Y&Z.		
3.5.9	Solderability	Solder wetting time shall be no more than 3 seconds. A new uniform coating of solder shall cover a minimum of 95% of the surface being				JESD22-B102E. e soldering.		
		immerged.		3				
		Environment I	Require	nents				
3.5.10	Thermal shock	Initial: 80 m Ω N Final: ΔR 25 m			working h -40 and 8 including	nated specimen at neight to 256 cycles 35°C with 30 minute 0~5 minute transit	s betwee e dwells	e
3.5.11	Heat test (non operational)	Initial: 80 m Ω N Final: ΔR 25 m			-	re 6. nated specimen at neight to 85+/-3 °C		ıl
	(mem operational)				•	6h. See Figure 4	, 55.7	
3.5.12	Cold test (non operational)	Initial: 80 m Ω N Final: ΔR 25 m			Subject mated specimen at nominal working height to -40+/-3 °C, 16h. See Figure 5.			
3.5.13	Heat test (operational)	Initial: $80 \text{ m} \Omega$ Max. Final: ΔR 25 m Ω Max.			Subject mated specimen at nominal working height to test condition as Figure 7.			Ţ
3.5.14	Cold test (operational)	Initial: 80 m Ω Max. Final: Δ R 25 m Ω Max.			-	nated specimen at neight to test condi		
	1	Figure 1 (co	ntinue	1)				
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3.5.15	Condensation test-	Initial: 80 m Ω Max.	Subject mated specimen at nominal
	operational	Final: ΔR 25 m Ω Max.	working height to test condition as
			Figure 9.
3.5.16	Sulfuration for gold	No physical damage shall	Subject mated specimens to the
	surface	occur.	environment:
		Initial: 80 m Ω Max.	H2S: 3ppm
		Final: ΔR 25 m Ω Max.	Temperature: 40+/-2℃
			Humidity: 75+/-3 %
			Duration: 24h
3.5.17	Peeling off strength	2N minimum in vertical to	Subject soldered specimens to the
		PCB direction.	test condition as
		15N minimum in Long pad	Figure 10(vertical to PCB direction)
		direction.	Figure 11(Long pad direction)
		10N minimum in Short pad	Figure 12(Short pad direction)
		direction.	
3.5.18	Resistance to re-flow	No physical damage shall	Subject specimens to reflow process
	soldering heat	occur.	for 3 times per IPC/JEDEC J-STD-20
			table 5-2.
			Moisture sensitivity should meet at
			lease level 2 per IPC/JEDEC J-STD-
			20, table 5-1.
3.5.19	Vibration Sinusoidal	No discontinuities of 1	Subject mated specimens at nomina
		microsecond or longer	working height to sinusoidal vibration
		duration.	over a specified frequency range of
		80 milliohms Max.(Initial)	10~500Hz. The X, Y and Z axes of
		ΔR 25 milliohms	the mated samples are subjected to
		Maximum.(Final)	sweep cycles/axis.
			Temperature: 23+/-5℃.
			Temperature: 23+/-5℃. Humidity: 35~70%RH.

Figure 1

Shall meet visual requirements, show no physical damage, and meet requirements of additional tests as specified in the Product Qualification and Requalification Test Sequence shown in Figure 2.

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3.6. Product Qualification and Requalification Test Sequence

	Test group										
Test Items	1	2	3	4	5	6	7	8	9	10	11
					Test s	equer	nce				
Initial examination of product	1	1	1	1	1	1	1	1	1	1	1
Terminal resistance (LLCR)		3,6	2,4,6		2,4,6	2, 4	2, 4		2,5	2, 4	
Contact force measurement	4,6										
Durability	5	4									
Shock, Operational										3	
Vibration, Random			3								
Vibration, Sinusoidal			5								
Temperature rise								2			
Solderability				2							
Cold test-non operation					5						
Heat test-non operation					3						
Cold test-Operation									4		
Heat test-Operation									3		
Condensation test-Operation		5									
Sulfuration for gold surface							3				
Thermal shock						3					
Resistance to soldering heat	2	2									
Peeling off											2
Final examination of product	3,7	7	7	3	7	5	5	3	6	5	3

- (a) Numbers indicate sequence in which tests are performed.
- (b) Precondition specimens with 10 durability cycles.

Figure 2

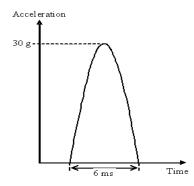


Figure 3

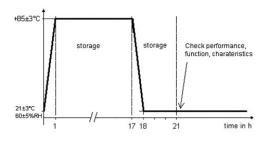
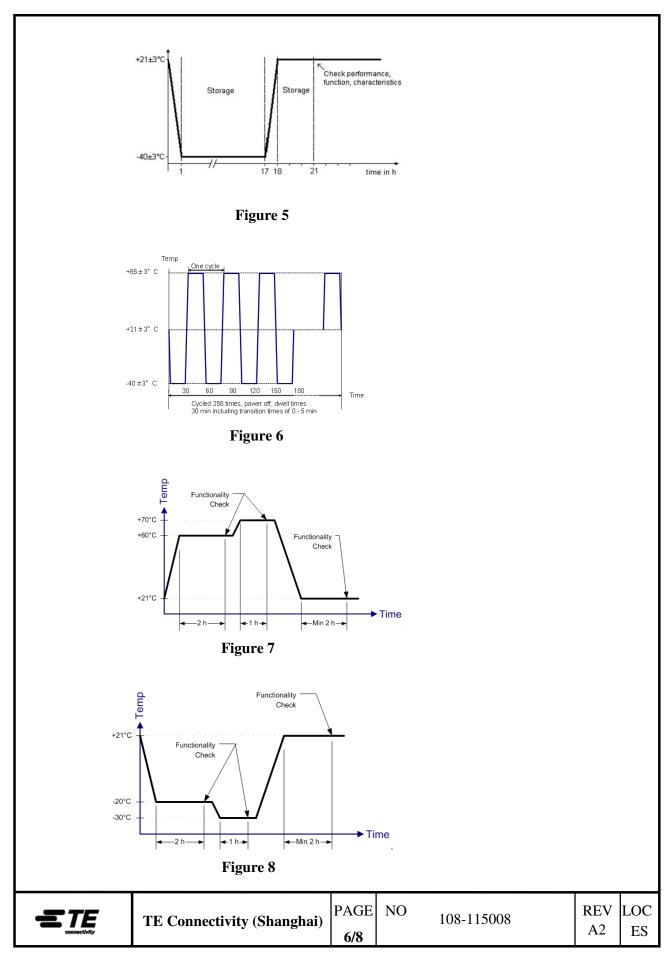
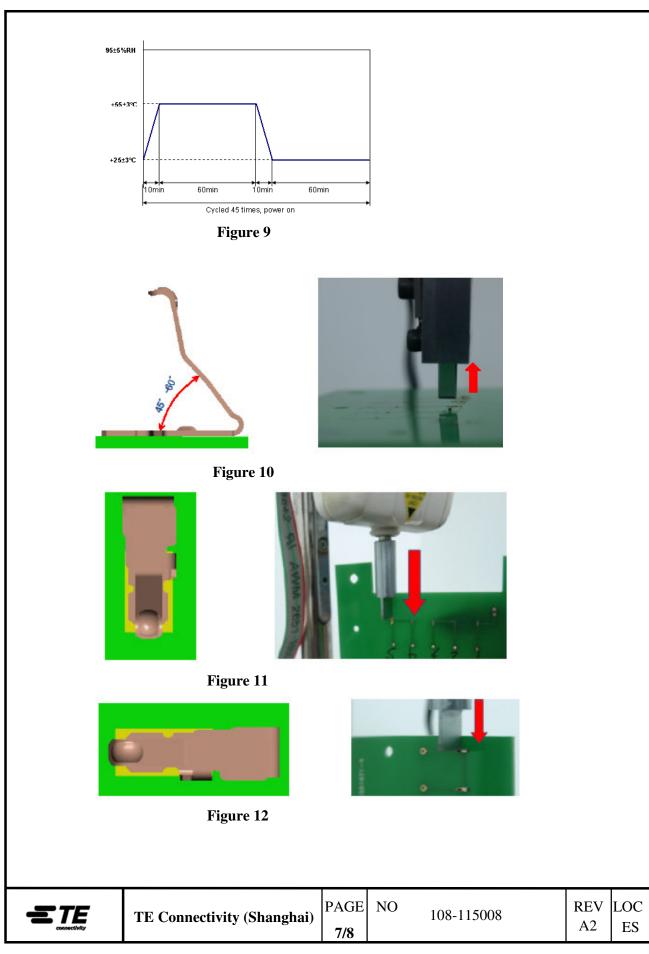


Figure 4

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The applicable products description and part numbers are as shown in appendix 1.

Part Number	Description	Qualification Test
1551631-4	Spring Finger 124	501-115009
1551572-4	Spring Finger 1.80	501-115009-1
1551573-4	Spring Finger 2.15	501-115009-2
1551574-4	Spring Finger 2.60	501-115009-3
1551575-4	Spring Finger 3.0	501-115009-4
1551576-4	Spring Finger 3.4	501-115009-5

Appendix 1

4. QUALITY ASSURANCE PROVISIONS

4.1. Qualification Testing

A. Specimen Selection

Specimens shall be prepared in accordance with applicable Instruction Sheets and shall be selected at random from current production. Each test group shall consist of a minimum of 5 specimens.

B. Test Sequence

Qualification inspection shall be verified by testing specimens as specified in Figure 1.

4.2. Regualification Testing

If changes significantly affect form, fit or functions are made to the product or manufacturing process, product assurance shall coordinate requalification testing, consisting of all or part of the original testing sequence as determined by development/product, quality and reliability engineering.

4.3. Acceptance

Acceptance is based on verification that the product meets the requirements of Figure 1. Failures attributed to equipment, test setup or operator deficiencies shall not disqualify the product. If product failure occurs, corrective action shall be taken and specimens resubmitted for qualification. Testing to confirm corrective action is required before resubmittal.

4.4. Quality Conformance Inspection

The applicable quality inspection plan shall specify the sampling acceptable quality level to be used. Dimensional and functional requirements shall be in accordance with the applicable product drawing and this specification.

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